

P-channel enhancement mode vertical D-MOS transistor

BSS84

FEATURES

- Low threshold voltage
- Direct interface to C-MOS, TTL, etc.
- High-speed switching
- No secondary breakdown.

PINNING - SOT23

PIN	SYMBOL	DESCRIPTION
1	g	gate
2	s	source
3	d	drain

APPLICATIONS

- Line current interrupter in telephone sets
- Relay, high speed and line transformer drivers.

DESCRIPTION

P-channel enhancement mode vertical D-MOS transistor in a SOT23 SMD package.

CAUTION

The device is supplied in an antistatic package.
The gate-source input must be protected against static discharge during transport or handling.

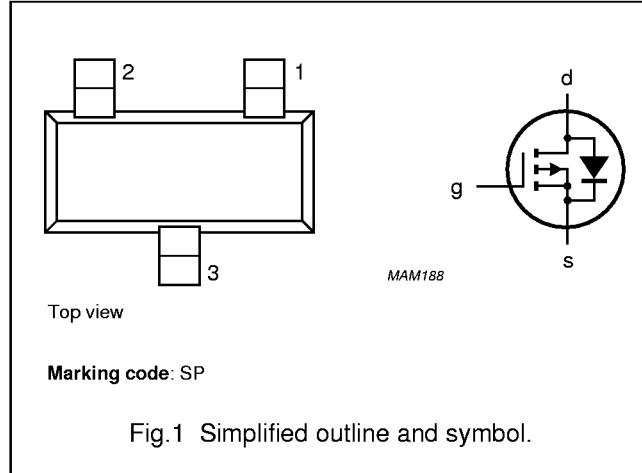


Fig.1 Simplified outline and symbol.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DS}	drain-source voltage (DC)		–	–50	V
V_{GSO}	gate-source voltage (DC)	open drain	–	± 20	V
V_{GSTh}	gate-source threshold voltage	$I_D = -1 \text{ mA}; V_{DS} = V_{GS}$	–0.8	–2	V
I_D	drain current (DC)		–	–130	mA
R_{DSon}	drain-source on-state resistance	$I_D = -130 \text{ mA}; V_{GS} = -10 \text{ V}$	–	10	Ω
P_{tot}	total power dissipation	$T_{amb} \leq 25^\circ\text{C}$	–	250	mW

P-channel enhancement mode
vertical D-MOS transistor

BSS84

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DS}	drain-source voltage (DC)		—	-50	V
V_{GSO}	gate-source voltage (DC)	open drain	—	± 20	V
I_D	drain current (DC)		—	-130	mA
I_{DM}	peak drain current		—	-520	mA
P_{tot}	total power dissipation	$T_{amb} \leq 25^\circ\text{C}$; note 1	—	250	mW
T_{stg}	storage temperature		-65	+150	$^\circ\text{C}$
T_j	operating junction temperature		—	150	$^\circ\text{C}$

THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
$R_{th\ j-a}$	thermal resistance from junction to ambient	note 1	500	K/W

Note to the Limiting values and Thermal characteristics

1. Device mounted on a printed-circuit board.

CHARACTERISTICS $T_j = 25^\circ\text{C}$ unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0$; $I_D = -10 \mu\text{A}$	-50	—	—	V
V_{GSth}	gate-source threshold voltage	$V_{DS} = V_{GS}$; $I_D = -1 \text{ mA}$	-0.8	—	-2	V
I_{DSS}	drain-source leakage current	$V_{GS} = 0$; $V_{DS} = -40 \text{ V}$	—	—	-100	nA
		$V_{GS} = 0$; $V_{DS} = -50 \text{ V}$	—	—	-10	μA
		$V_{GS} = 0$; $V_{DS} = -50 \text{ V}$; $T_j = 125^\circ\text{C}$	—	—	-60	μA
I_{GSS}	gate leakage current	$V_{DS} = 0$; $V_{GS} = \pm 20 \text{ V}$	—	—	± 10	nA
R_{DSon}	drain-source on-state resistance	$V_{GS} = -10 \text{ V}$; $I_D = -130 \text{ mA}$	—	—	10	Ω
$ y_{fs} $	forward transfer admittance	$V_{DS} = -25 \text{ V}$; $I_D = -130 \text{ mA}$	50	—	—	mS
C_{iss}	input capacitance	$V_{GS} = 0$; $V_{DS} = -25 \text{ V}$; $f = 1 \text{ MHz}$	—	25	45	pF
C_{oss}	output capacitance	$V_{GS} = 0$; $V_{DS} = -25 \text{ V}$; $f = 1 \text{ MHz}$	—	15	25	pF
C_{rss}	reverse transfer capacitance	$V_{GS} = 0$; $V_{DS} = -25 \text{ V}$; $f = 1 \text{ MHz}$	—	3.5	12	pF

Switching times (see Figs 2 and 3)

t_{on}	turn-on time	$V_{GS} = 0$ to -10 V ; $V_{DD} = -40 \text{ V}$; $I_D = -200 \text{ mA}$	—	3	—	ns
t_{off}	turn-off time	$V_{GS} = -10$ to 0 V ; $V_{DD} = -40 \text{ V}$; $I_D = -200 \text{ mA}$	—	7	—	ns

P-channel enhancement mode
vertical D-MOS transistor

BSS84

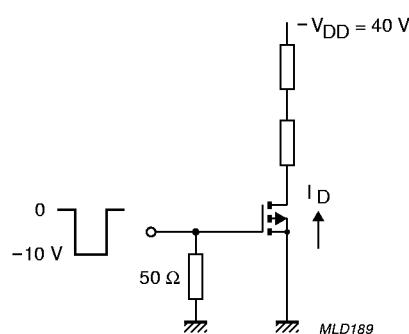


Fig.2 Switching time test circuit.

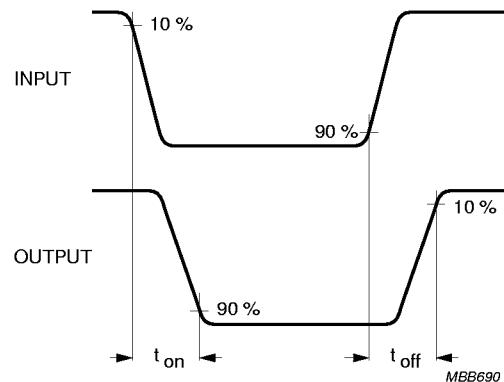


Fig.3 Input and output waveforms.

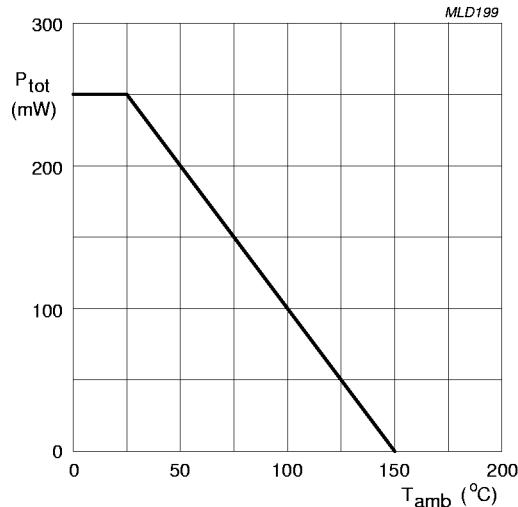
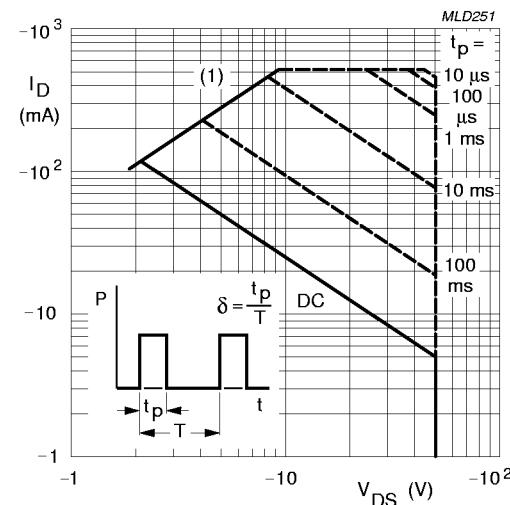


Fig.4 Power derating curve.

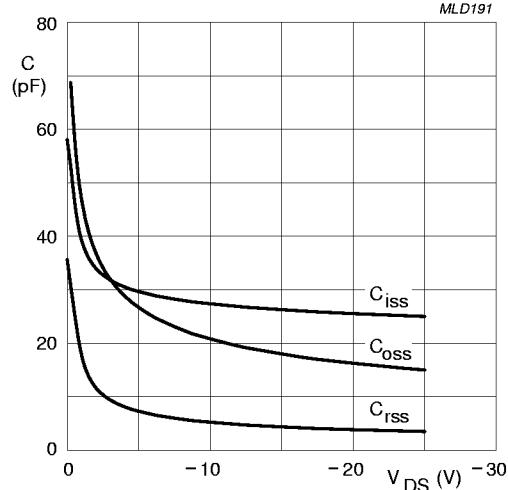


$\delta = 0.01$.
 $T_{amb} = 25 \text{ }^{\circ}\text{C}$.
(1) R_{DSon} limitation.

Fig.5 DC SOAR.

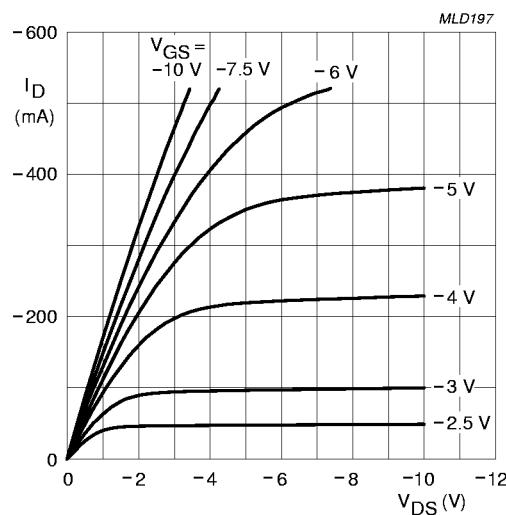
P-channel enhancement mode
vertical D-MOS transistor

BSS84



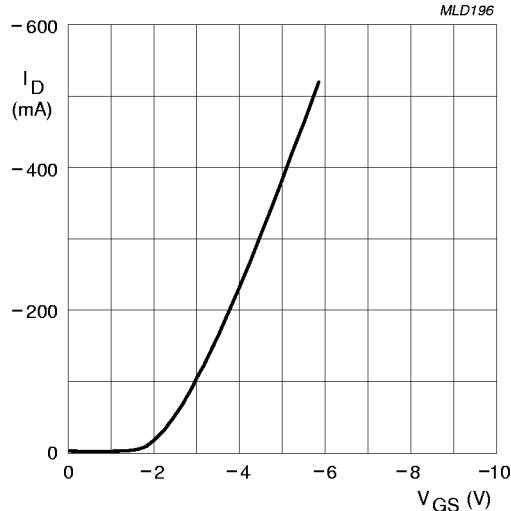
$V_{GS} = 0$; $T_j = 25^\circ\text{C}$; $f = 1 \text{ MHz}$.

Fig.6 Capacitance as a function of drain source voltage; typical values.



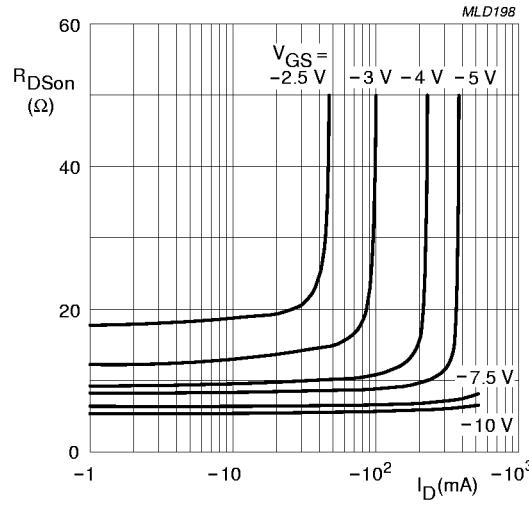
$T_j = 25^\circ\text{C}$.

Fig.7 Typical output characteristics.



$V_{DS} = -10 \text{ V}$; $T_j = 25^\circ\text{C}$.

Fig.8 Typical transfer characteristics.

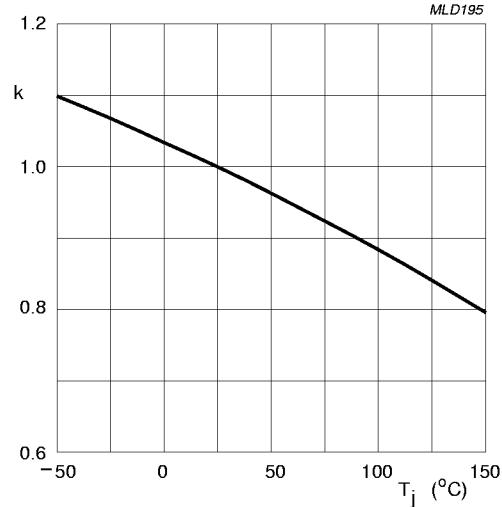


$T_j = 25^\circ\text{C}$.

Fig.9 Drain-source on-state resistance as a function of drain current; typical values.

P-channel enhancement mode
vertical D-MOS transistor

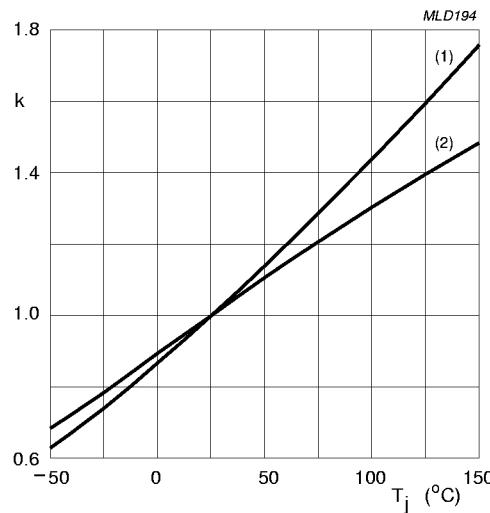
BSS84



$$k = \frac{V_{GS\text{th}} \text{ at } T_j}{V_{GS\text{th}} \text{ at } 25^{\circ}\text{C}}$$

$I_D = -1 \text{ mA}$; $V_{DS} = V_{GS}$.

Fig.10 Temperature coefficient of gate-source threshold voltage.

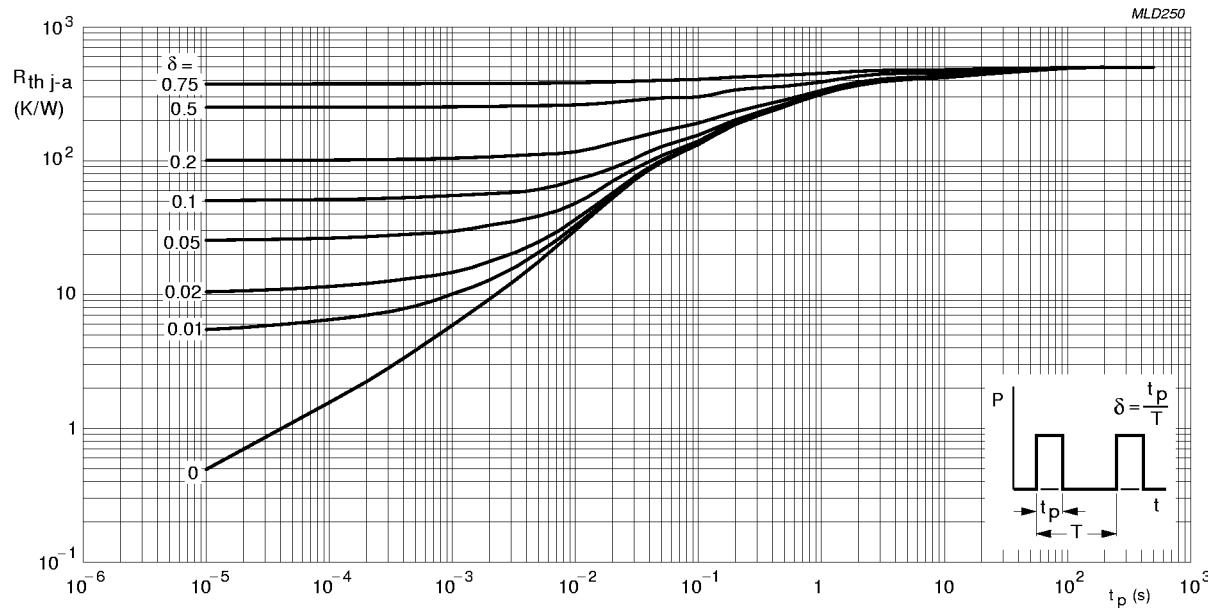


$$k = \frac{R_{DS\text{on}} \text{ at } T_j}{R_{DS\text{on}} \text{ at } 25^{\circ}\text{C}}$$

(1) $I_D = -130 \text{ mA}; V_{GS} = -10 \text{ V}$.

(2) $I_D = -20 \text{ mA}; V_{GS} = -2.4 \text{ V}$.

Fig.11 Temperature coefficient of drain-source on-state resistance.



$T_{amb} = 25^{\circ}\text{C}$.

Fig.12 Thermal resistance from junction to ambient as a function of pulse time; typical values.

P-channel enhancement mode
vertical D-MOS transistor

BSS84

PACKAGE OUTLINE

Plastic surface mounted package; 3 leads

SOT23

